

A. Authors, institutions, Overview

- ① 1. Title – Enter a title, beginning with a descriptive reference to the specimen material or other characteristics specific to this data record, e.g. "Polyvinyl Acetate Degradation During XPS Measurements." Please refrain from using titles beginning with the name of the spectroscopy, e.g. avoid titles like "AES Study of . . ."

CuI by XPS

2. Authors, Institutions, and Locations (city, state, province, or country) – List authors and affiliations, in order of appearance in SSS.

<u>Richard P. Vasquez</u>	<u>Jet Propulsion Laboratory</u>	<u>California Institute of Technology</u>	<u>Pasadena, CA</u>	<u>91109-3099</u>
Author	Institution		Location	

Author	Institution	Location

- ① 3. Abstract — Summarize and include key information about the specimens and spectra, such as specimen material measurement procedures, and significance of the research. The abstract will be reprinted verbatim.

X-ray photoemission measurements of high purity CuI are presented. XPS studies of Cu compounds in this laboratory have been motivated by the need to identify species on chemically-etched high temperature superconductor surfaces (e.g., see Ref. 1).

- ① 9. Key Words - list selected phrases and words to help readers search for information in the database, e.g. Auger electron spectroscopy, oxidation, corrosion, surface segregation. Be selective, but thorough.

X-ray photoemission, copper (I) iodide, copper compounds

- ① 10. Spectra Category - Check the suggested category of the data record: Technical, Comparison, or Reference (see the overview of instructions for definitions). The editors may suggest an alternate category, based on the recommendations of referees,

Technical Comparison Reference

- ③ 11. References - List citations to articles related to the data record using the style of J. Vac. Sci. Technol.

1. R.P. Vasquez, M. C. Foote, and B. D. Hunt, J. Appl. Phys.
66 4866 (1989).

- ⑤ 12. Acknowledgements

This work was supported by NASA/CACT and BMDO/EST.

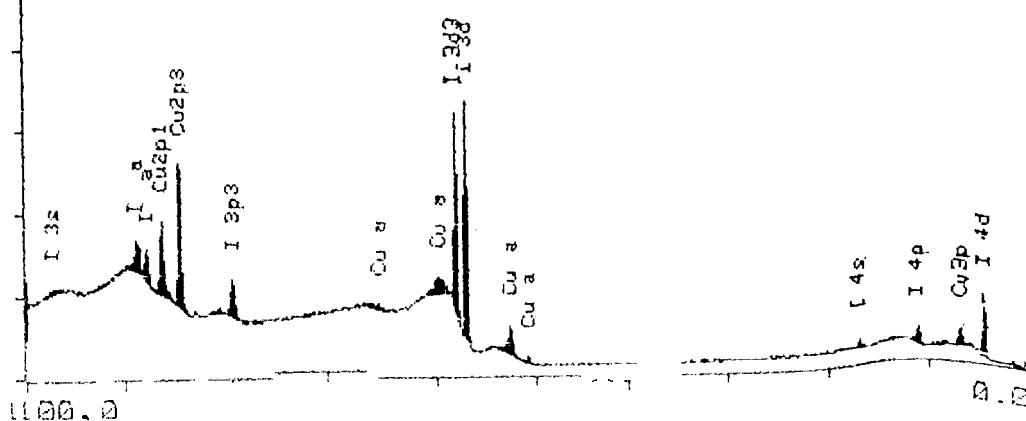
Monday 11/29/1993
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CuI compressed on In

50000 Oper: RPV Groups: B Res: 4 Spot: 1000 u

(1) CuI_1

of Scans 1
Flood Gun 1098.93
eV Counts 8400



SURFACE COMPOSITION TABLE

CuI_1
CuI compressed on In

Elem.	Corr'd Flood Gun	Delta BE	Sens Factor	# of Scans	eV	Area	Relative Area	Atom %
Cu2p3	932.42	0.0	-1.42	9.748	1	137.5	49937	550324 51.65
I 3d5	618.75	0.0	1.25	15.303	1	137.5	75782	515135 48.35